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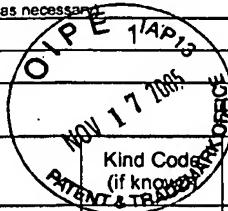
Application Number 10/672,889

Filing Date September 26, 2003

First Named Inventor: James J. Synder et al.

Examiner Name MICHAEL A LYONS

Attorney Docket Number 033806-010



U. S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
/HL/	Snyder, J.J., "Algorithm for fast digital analysis of interference fringes", <i>Applied Optics</i> 19, 1223 (1980).
/HL/	J.H. Bruijn, "Fringe Scanning Interferometers", in <i>Optical Shop Testing</i> , Daniel Malacara, ed. (John Wiley and Sons, New York, 1978) 409-437.
/HL/	Katherine Creath, "Phase-Measurement Interferometry Techniques," in <i>Progress in Optics</i> XXXVI, E. Wolf, ed. (North-Holland, Amsterdam, 1988), 349-393.

Examiner Signature	/Hwa Lee/	Date Considered	08/07/2007
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.
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